

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		"5876902".PN.	USPAT	OR	OFF	2004/08/08 20:56
L1	97	fan near out near configuration	USPAT	OR	ON	2006/04/28 13:12
L2	5561	257/758	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:30
L3	1148	257/759	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:41
L4	1355	257/760	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:55
L5	3	257/E21.526	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:56
L6	2	257/E21.575	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:56
L7	2499	357/80	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 14:00
L8	5163	430/311	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 14:00

## EAST Search History

S1	21743	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) with (semiconductor or die or chip or dice or IC)	USPAT	OR	ON	2006/04/26 21:03
S2	21662	(bad or defect\$3 or "non functional" ) with (semiconductor or die or chip or dice or IC)	USPAT	OR	ON	2004/08/08 20:31
S3	5340	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC)	USPAT	OR	ON	2004/08/08 20:32
S4	5336	(bad or defect\$3 or "non functional" or (none or "not" or non) adj function\$2) near (semiconductor or die or chip or dice or IC)	USPAT	OR	ON	2004/08/08 20:32
S5	2980	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer	USPAT	OR	ON	2004/08/08 20:38
S6	1326	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and wafer) and (repair\$3 or reconfigur\$3 or isolat\$3)	USPAT	OR	ON	2004/08/08 20:34
S7	206	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with (repair\$3 or reconfigur\$3 or isolat\$3) and wafer	USPAT	OR	ON	2004/08/08 20:57
S8	1	"5255051".PN.	USPAT	OR	OFF	2004/08/08 20:55
S9	1	"5327338".PN.	USPAT	OR	OFF	2004/08/08 20:55
S10	1	"5386221".PN.	USPAT	OR	OFF	2004/08/08 20:55
S11	1	"5786632".PN.	USPAT	OR	OFF	2004/08/08 20:55
S12	1	"5876902".PN.	USPAT	OR	OFF	2004/08/08 20:55
S13	1	"5895581".PN.	USPAT	OR	OFF	2004/08/08 20:56
S14	1	"5255051".PN.	USPAT	OR	OFF	2004/08/08 20:56
S15	1	"5255051".PN.	USPAT	OR	OFF	2004/08/08 20:56
S16	1	"5327338".PN.	USPAT	OR	OFF	2004/08/08 20:56

## EAST Search History

S17	1	"5386221".PN.	USPAT	OR	OFF	2004/08/08 20:56
S18	1	"5786632".PN.	USPAT	OR	OFF	2004/08/08 20:56
S19	1	"6262390".PN.	USPAT	OR	OFF	2004/08/08 20:56
S20	1	"6115175".PN.	USPAT	OR	OFF	2004/08/08 20:56
S21	1	"6088379".PN.	USPAT	OR	OFF	2004/08/08 20:56
S22	1	"6048753".PN.	USPAT	OR	OFF	2004/08/08 20:56
S23	1	"6037967".PN.	USPAT	OR	OFF	2004/08/08 20:56
S24	1	"5990566".PN.	USPAT	OR	OFF	2004/08/08 20:56
S25	1	"5895581".PN.	USPAT	OR	OFF	2004/08/08 20:56
S26	1	"5876902".PN.	USPAT	OR	OFF	2004/08/08 20:56
S27	1	"5786632".PN.	USPAT	OR	OFF	2004/08/08 20:56
S28	1	"5386221".PN.	USPAT	OR	OFF	2004/08/08 20:56
S29	1	"5327338".PN.	USPAT	OR	OFF	2004/08/08 20:56
S30	1	"5255051".PN.	USPAT	OR	OFF	2004/08/08 20:56
S31	1	"6262390".PN.	USPAT	OR	OFF	2004/08/08 20:58
S32	1	"6115175".PN.	USPAT	OR	OFF	2004/08/08 20:58
S33	1	"6088379".PN.	USPAT	OR	OFF	2004/08/08 20:58
S34	1	"6048753".PN.	USPAT	OR	OFF	2004/08/08 20:58
S35	1	"6037967".PN.	USPAT	OR	OFF	2004/08/08 20:58
S36	1	"5990566".PN.	USPAT	OR	OFF	2004/08/08 20:59
S37	1	"5895581".PN.	USPAT	OR	OFF	2004/08/08 20:59
S38	1	"5876902".PN.	USPAT	OR	OFF	2004/08/08 20:59
S39	1	"5786632".PN.	USPAT	OR	OFF	2004/08/08 21:00
S40	1	"5386221".PN.	USPAT	OR	OFF	2004/08/08 21:00
S41	1	"5327338".PN.	USPAT	OR	OFF	2004/08/08 21:00
S42	1	"5255051".PN.	USPAT	OR	OFF	2004/08/08 21:01
S43	13	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electrically near (isolat\$3)	USPAT	OR	OFF	2004/08/09 00:44
S44	16	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electric\$4 near (isolat\$3)	USPAT	OR	OFF	2004/08/09 00:43

## EAST Search History

S45	0	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) with electric\$4 near (isolat\$3)) and burn near in near test	USPAT	OR	OFF	2004/08/09 00:43
S46	28	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test	USPAT	OR	OFF	2004/08/09 00:44
S47	30	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3	USPAT	OR	OFF	2004/08/09 00:44
S48	47	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3	USPAT	OR	ON	2004/08/09 00:48
S49	12	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) and burn near in near test\$3) and electric\$4 with isolat\$3	USPAT	OR	ON	2004/08/09 01:34
S50	0	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same burn near in near test\$3	USPAT	OR	ON	2004/08/09 01:33
S51	9	"5829128" and "6032356"	USPAT	OR	ON	2004/08/09 01:25
S52	65	"5829128" or "6032356"	USPAT	OR	ON	2004/08/09 01:25
S53	179	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3	USPAT	OR	ON	2004/08/09 01:34

## EAST Search History

S54	17	((bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) near (semiconductor or die or chip or dice or IC) same (burn near in or "burn-in") near test\$3) and electric\$4 with isolat\$3	USPAT	OR	ON	2004/08/09 03:40
S55	2	"6600171".pn. or "6680213".pn.	USPAT	OR	ON	2004/08/09 03:47
S56	1972	257/750	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 03:50
S57	2657	257/690	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 03:56
S58	1973	257/691	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 04:08
S59	2650	257/700	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 04:22
S60	4668	257/758	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 05:30
S61	2	"5543364".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 05:25
S62	923	257/759	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 05:43
S63	1671	257/779	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/08/09 05:44
S64	5	"6214630"	USPAT	OR	OFF	2005/01/21 12:20

## EAST Search History

S65	1	"6214630" and redistribution	USPAT	OR	OFF	2005/01/21 12:21
S66	1	"6214630" and redistribution and defective and repair	USPAT	OR	OFF	2005/01/21 12:22
S67	3	438/128-132.ccls. and defect\$3 and redistribution and repair	USPAT	OR	OFF	2005/01/21 19:35
S68	1376	burn-in near testing	USPAT	OR	OFF	2005/01/21 19:35
S69	760	burn-in near testing and wafer	USPAT	OR	OFF	2005/01/21 20:33
S70	1	"5594273".pn. and burn-in near test\$3	USPAT	OR	OFF	2005/01/21 21:06
S71	1	"6472239".pn.	USPAT	OR	OFF	2005/01/21 21:07
S72	2128	438/128	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/21 21:08
S73	1007	438/129	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/21 21:21
S74	297	438/130	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/21 21:33
S75	372	438/131	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/21 21:40
S76	511	438/132	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/01/21 21:40
S77	4745	257/758	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:20

## EAST Search History

S78	1002	257/759	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 16:08
S79	1179	257/760	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/12 16:08
S80	5168	257/758	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/25 22:04
S81	1080	257/759	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/25 22:47
S82	1262	257/760	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/10/25 22:47
S83	4423	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) with (semiconductor or die or chip or dice or IC) with wafer	USPAT	OR	ON	2006/04/26 21:04
S84	200	(bad or defect\$3 or "non functional" or (none or "not" or non) near function\$2) with (semiconductor or die or chip or dice or IC) with wafer same repair\$3	USPAT	OR	ON	2006/04/26 21:04
S85	2499	357/80	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/04/28 13:12